Electronic supplementary information for the manuscript

Molecular structure – electrical performance relationship for OFETbased memory elements comprising unsymmetrical photochromic diarylethenes

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Experimental procedures

Materials and Instrumentation

The devices were fabricated using a procedure described previously (L. I. Leshanskaya et al., *Adv. Optical Mater.*, 2017, 5, 1601033) with small modifications. Aluminum gate electrodes (180 nm thick) were deposited by thermal evaporation in vacuum (2×10^{-6} mbar) through a shadow mask. Thin layer of AlO_x (~10 nm) was grown via electrochemical anodic oxidation of aluminum gate electrodes in 0.1 M citric acid (Acros Organics) at a constant potential of 35 V for 6 min. Afterwards, the photochromic layer of a diarylethene **TO-0**, **TO-1** or **TO-2** (with the thickness 60-100 nm) was formed by spin-coating 25 μ L of 10 mg/mL toluene solution atop AlO_x at 750 rpm inside a nitrogen glove box. Then the samples were transferred to the vacuum chamber, where fullerene C₆₀ (32-70 nm) was deposited by thermal evaporated through a shadow mask to form the source and drain electrodes with a channel length and width of 80 μ m and 2 mm, respectively. The layer thicknesses were confirmed by depositing the single-component films on glass in the same regime as while fabricating the device and profiling them through a scratch in a contact mode using NTEGRA PRIMA NT-MDT probe microscope.

Measuring the electrical characteristics of OFET-based memory devices

The procedure was essentially the same as reported previously (L. A. Frolova et al., *Chem. Commun.*, 2015, 51, 6130–6132). The electrical characterization of the devices was performed using a double-channel Keithley 2612A instrument. While programming the memory elements, an electrical bias between the source and gate electrodes of the transistor (programming voltage V_p) and illumination provided by diode laser (405 nm, ~60 mW·cm⁻²) were applied simultaneously. The length of the single laser pulse was modulated within the range from 1 ms to 60 s using Advantest R6240A voltage current source/monitor. The transfer characteristics of the transistors and drain currents at constant gate voltage were registered after each programming step. All measurements were carried out inside a nitrogen glove box with <1 ppm O_2 and < 1 ppm H_2O .

Light-enhanced spin resonance (LESR) spectroscopy

To perform light-induced electron spin resonance measurements, composite films comprised of diarylethene **TO-1**, C_{60} and [60]PCBM with a mass ratio of the components equal to 1:1:1 were deposited on the walls of ESR quartz tubes from chlorobenzene solution. [60]PCBM was added to improve the miscibility of the components and overall uniformity of the films. Similarly, reference samples of individual C_{60} or dihetarylethenes were prepared. Measurements were performed using Radiopan SE/X-2544 spectrometer in dark and under illumination with laser light λ =405 nm at 123 K (liquid nitrogen cooling) and also in dark at room temperature (273 K).

Table S1. Spectral properties of diarylethenes **TO-0**, **TO-1** and **TO-2** before and after exposure to UV light (365 nm) in acetonitrile

Me N Me O Ph Vis Me O Ph					
(open isomer A closed isomer		r B		
Diarylethene	Structure	$\lambda_{max}{}^{A}$, nm	$\lambda_{max}{}^{B}$, nm		
		(ε, M ⁻¹ ·cm ⁻¹) ^a	(ε, M ⁻¹ ·cm ⁻¹)		
то-0	Me N Me S Me O Ph	290 (16500)	452 (8900)		
TO-1	Me N Me S Me O Ph	298 (26000)	523 (7600)		
то-2	Me N Me S Me O Ph	284 (24300)	549 (6000)		



Figure S1. Absorption spectra of compounds **TO-0**, **TO-1** and **TO-2** before exposure to UV light (in acetonitrile, $C = 2.7 \times 10^{-5}$ M).



Figure S2. Absorption spectra of compounds **TO-0**, **TO-1** and **TO-2** after exposure to UV light (365 nm) in acetonitrile ($C = 2.7 \times 10^{-5}$ M).



Figure S3. SEM image of the OFET cross-section.



Figure S4. SEM images of 1:1 (w/w) blend films comprising of diarylethene **TO-0** (a), **TO-1** (b) or **TO-2** (c) and C_{60} in two different magnifications.



Figure S5. Evolution of the transfer characteristics of the devices comprising **TO-0** under simultaneous exposure to a negative (a) or positive (b) applied bias voltage ($V_P = -5 V \text{ or } +5 V$) and violet light ($\lambda = 405 \text{ nm}$) as a function of the programming time.



Figure S6. Evolution of the transfer characteristics of the devices comprising **TO-1** under simultaneous exposure to a negative (a) or positive (b) applied bias voltage ($V_P = -5 V \text{ or } +5 V$) and violet light ($\lambda = 405 \text{ nm}$) as a function of the programming time.



Figure S7. Evolution of the transfer characteristics of the devices comprising **TO-2** under simultaneous exposure to a negative (a) or positive (b) applied bias voltage ($V_P = -5 V \text{ or } +5 V$) and violet light ($\lambda = 405 \text{ nm}$) as a function of the programming time.



Figure S8. Evolution of the transfer characteristics of the devices comprising **TO-0** under simultaneous exposure to violet light (λ = 405 nm) and electric bias (both applied for a fixed programming time t_P = 100 ms) as a function of the bias voltage.



Figure S9. Evolution of the transfer characteristics of the devices comprising **TO-1** under simultaneous exposure to violet light (λ = 405 nm) and electric bias a function of the bias voltage. The programming times were fixed at 100 ms (a) and 2 s (b).



Figure S10. Evolution of the transfer characteristics of the devices comprising **TO-2** under simultaneous exposure to violet light (λ = 405 nm) and electric bias a function of the bias voltage. The programming time was fixed at 100 ms (a) and 10 ms (b).



Figure S11. The absorption spectra of thin films of C_{60} , TO-1 and bilayer film TO-1/ C_{60} .



Figure S12. ESR spectra of an individual C_{60} film recorded at 123K in dark and under illumination with violet light (405 nm) showing no photoinduced signals.



Figure S13. Proposed stabilization of the positive charge via oxidative cyclization of **TO-0** (a). Schematic switching mechanism for OFETs comprising **TO-0** (b).